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Application/Control No.	Applicant(s)/Patent under Reexamination
10/718,718	CHEN, EDEN JUNG-YU
Examiner	Art Unit
Brian A. Zimmerman	2635

	SEARCHED			
	JEAN		i	
Class	Subclass	Date	Examiner	
340	5.26 5.23 5.24 5.25 5.73 5.67	2/28/2006	BAZ	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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